

## POSTER SESSION II

19 September 2006 (Tuesday) 14.30-16.30

### a. CLUSTER ION BEAMS

- P - 59 **Large-scale molecular dynamics simulation for two Ar clusters impact on 4H-SiC**  
*Shin-ichi Satake, Tomoaki Kunugi, Masahiko Shibahara, Hirokazu Kasahara, Natsuki Inoue*
- P - 60 **Damage characteristics of low-temperature BSi molecular ion implantation in silicon**  
*Jenq-Hong Liang, Shih-Chang Wang*
- P - 102 **Molecular dynamics simulations of a surface smoothing process with glancing angle gas cluster ion beams**  
*Takaaki Aoki, Jiro Matsuo*
- P - 103 **Unique characteristics of oblique irradiation of gas cluster ion beam**  
*Akiko Suzuki, Emmanuel Bourelle, Akinobu Sato*
- P - 140 **Formation of surface nanostructures on implantation of Ar clusters into HOPG**  
*V. N. Popok, E.E.B. Campbell*
- P - 201 **Cascade Overlap and the Size Effect in Energetic Cluster Impacts on Solids**  
*Maxim Ponomarev, Roger P. Webb*
- P - 232 **Molecular effect in GaN bombarded by cluster ions**  
*Alexander Yu. Azarov, Andrei I. Titov, Sergei O. Kucheyev*
- P - 256 **Surface Smoothing of Compound Semiconductor SiC Using Gas Cluster Ion Beam**  
*T. Ichihashi, T. Suzuki, M. Ebata, N. Miyatake, K. Murata*
- P - 312 **TOF Mass spectrometry of secondary ions from HOPG target bombarded by fast cluster ion beams**  
*Hiroshi Shibata, H. Tsuchida, A. Itoh, Y. Saitoh, A. Chiba, K. Narumi, K. Arakawa*
- P - 335 **Irradiation characteristics of metal-cluster-complex ions containing diverse multi-elements with large mass differences**  
*Yukio Fujiwara, Kouji Kondou, Yoshikazu Teranishi, Hidehiko Nonaka, Naoaki Saito, Toshiyuki Fujimoto, Akira Kurokawa, Shingo Ichimura, Mitsuhiro Tomita*
- P - 336 **Low-damage surface smoothing of laser crystallized polycrystalline silicon using gas cluster ion beam**  
*Hidetada Tokioka, Hiroya Yamarin, Toshiaki Fujino, Mitsuo Inoue*
- P - 338 **Experimental study of dependence of sputtering yields on cluster size**  
*Noriaki Toyoda, Isao Yamada*
- P - 361 **High-speed processing with high-energy SF<sub>6</sub> cluster ion beam**  
*Toshio Seki, Jiro Matsuo*
- P - 395 **Characteristics of cluster size selector using high frequency deflector for large cluster ions**  
*Kiyoto Owaki, Yoshiaki Takatani*
- P - 404 **A sputtered Si surface irradiated by metal cluster complex ions such as Os<sub>3</sub>(CO)<sub>12</sub> and Ir<sub>4</sub>(CO)<sub>12</sub>**  
*Y. Teranishi, K. Kondou, Y. Fujiwara, H. Nonaka, T. Fujimoto, S. Ichimura, M. Tomita*
- P - 434 **Low damage smoothing of magnetic material films using gas cluster ion beam**  
*Shigeru Kakuta, Shinji Sasaki, Tatsumi Hirano, Kazuhiro Ueda*
- P - 543 **Study of Si wafer surface irradiated by gas cluster ion beams**  
*E. Toyoda, H. Isogai, T. Senda, K. Izunome, K. Kashima, N. Toyoda, I. Yamada*

### b. ION BEAM MODIFICATIONS OF SEMICONDUCTORS

- P - 13 **Crystalline quality of 3C-SiC synthesized by high-dose C-ion implantation in Si**  
*S. Intarasiri, A. Hallén, J. Lu, J. Jensen, L.D. Yu, K. Bertilsson, S. Singkarat, G. Possnert*
- P - 87 **Influence of implantation and annealing parameters on the Si nanocrystals photoluminescence produced by Si hot implantation**  
*Uilson S. Sias, Moni Behar, Henri Boudinov, Eduardo C. Moreira*
- P - 89 **Behavior of ion beam induced defects in light-emitting Si nanocrystals**  
*Gregory A. Kachurin, Svetlana G. Cherkova, Denis V. Marin, Anton K. Gutakovsky, Alexandr G. Cherkov, Vladimir A. Volodin*
- P - 94 **Electrical characterization of low temperature proton irradiated n-ZnO**  
*Michael Hayes, F. Danie Auret, Jackie Nel, Werner Wesch, Elke Wendler*
- P - 96 **Influence of crystal mosaicity on lattice site location experiments of impurities implanted into nitrides**  
*Bart De Vries, Ulrich Wahl, Joao Guilherme Correia, Sandra Ruffenach, Olivier Briot, André Vantomme, the ISOLDE Collaboration*
- P - 120 **Optical properties and application of GaSb implanted with 300 keV <sup>112</sup>Cd ions**  
*S. D. Pandey, S. K. Dubey, R. L. Dubey, A. D. Yadav, S. J. Gupta, M. R. Gokhale, B. M. Arora*

- P - 126 Room temperature relaxation of amorphous InP, GaAs and InAs characterized with the perturbed angular correlation technique**  
*Rakesh Dogra, Aidan P. Byrne, Mark C. Ridgway*
- P - 134 Effect of Laser annealing on refractive indices of rf sputtered amorphous SiC thin films**  
*Manoj Arora, S. Koka, Swati Arora*
- P - 142 Lattice location of F in preamorphized Si**  
*Fabiano Bernardi, José Henrique Rodrigues dos Santos, Moni Behar*
- P - 145 Formation of thicker buried oxide layer of SIMOX SOI materials using ion-induced defects process**  
*Jing Chen, Jiayin Sun, Aimin Wu, Zixin Lin, Xi Wang*
- P - 146 Research on Ion Implantation Effect on SIMOX Material Modification Technique by XPS Method**  
*E. X. Zhang, Zh. X. Zhang, J. Chen, Zh. R. Song, H. Yang, W. He, H. Tian, X. Wang*
- P - 152 Short-range thermal and structural properties of Ge nanocrystals**  
*Leandro L. Araujo, Patrick Kluth, Gustavo de M. Azevedo, Mark C. Ridgway*
- P - 156 Mn-silicite nanoparticles: the origin of ferromagnetism in Mn-implanted Si?**  
*S. Zhou, K. Potzger, G. Zhang, A. Mücklich, F. Eichhorn, N. Schell, R. Grötzschel, B. Schmidt, W. Skorupa, M. Helm, J. Fassbender*
- P - 161 SiC formation by methane ion implantation in Si**  
*Vahid Fathollahi, Omid Reza Kakuee, Hassan Dibaji, Mohammad Lamehi-Rachti, Majid Mojtahedzadeh Larijani*
- P - 166 Control of the crystalline quality of wurtzitic GaN films deposited on  $\gamma$ -LiAlO<sub>2</sub> by ion beam assisted molecular beam epitaxy**  
*Jürgen W. Gerlach, Andreas Hofmann, Thomas Höche, Bernd Rauschenbach*
- P - 167 Electrical characterization of rare-earth implanted gallium nitride**  
*Vasco Matias, André Vantomme, P. J. Janse van Rensburg, F.D. Auret*
- P - 171 Ion bombardment isolation of  $\delta$ -doped layers in GaAs**  
*Henri Boudinov, Giovanni C. Pesenti, Iuri Danilov*
- P - 173 Effect of the substrate temperature during implantation of Eu in GaN**  
*Vasco Matias, Ester Tooten, André Vantomme*
- P - 175 Nanoindentation-induced phase changes in ion-implanted silicon**  
*Simon Ruffell, Jodie E. Bradby, Jim S. Williams*
- P - 183 Optical properties GaAs/CaF<sub>2</sub> nanofilms variable thickness**  
*Baltahadja E. Umirzakov, Dilnoza A. Tashmukhamedova, Bahodir A. Kadirov, Dilshod M. Murodkobilov*
- P - 187 Dual energy Si ion implantation in epitaxial GaN layers on AlN/Al<sub>2</sub>O<sub>3</sub>**  
*Daisuke Ozaki, Jiro Ebihara, Yasunori Oshima, Ryosuke Takeuchi, Taroh Inada*
- P - 192 Nanocluster formation in Ge + Sn implanted SiO<sub>2</sub> layers**  
*Peter Gaiduk, Stanislav Prokoph'ev, Werner Wesch, Arne Nylandsted Larsen*
- P - 198 Characterization of n-type layers formed in (11-20)-4H-SiC by phosphorus ion implantation**  
*Naohito Yanagida, Kazuaki Ishibashi, Satoshi Uchiumi, Toroh Inada*
- P - 203 Optical properties on Er, Yb implanted Al<sub>0.70</sub>Ga<sub>0.30</sub>As**  
*Tomoyuki Arai, Shin-ichiro Uekusa, Akira Uedono*
- P - 211 Dynamics of photoionization, heating and crystallization of implanted silicon during laser annealing**  
*Gennadii D. Ivlev, Elena I. Gatzkevich, Rustem M. Bayazitov, Raphael I. Batalov, Ildus B. Khaibullin*
- P - 221 Nonlinear optical properties of transparent semiconductors with implanted metal nanoparticles**  
*Andrey L. Stepanov, Rustam I. Khaibullin, Nurdogan Can, Alexander Rysnanskiy, Bruno Palplant*
- P - 233 Formation of amorphous layers in silicon**  
*Erwan Olivier, Amy Gandy, Paulo F. P. Fichtner, Steve E. Donnelly, Marie France Beaufort, Jean Francois Barbot*
- P - 234 Angular dependence of defect formation in H-implanted silicon studied using deep level transient spectroscopy**  
*Jeffrey C. McCallum, Byron J. Willis*
- P - 238 Synthesis of buried silicon nitride layer in SiC by nitrogen implantation**  
*Alexander V. Suvorov, Alexandra A. Suvorova*
- P - 245 Excess vacancies in high energy ion implanted SiGe**  
*Reinhard Köegler, A. Peeva, A. Mücklich, A. Kuznetsov, J. Christensen, W. Skorupa, B.G. Svensson*
- P - 248 Speeding up GaAs semiconductor devices with ion irradiation damage**  
*Carolina Björkas, Kai Nordlund, Kai Arstila, Juhani Keinonen, Veer D. S. Dhaka, Markus Pessa*
- P - 259 Epitaxial lateral overgrown GaN implanted with Eu ions**  
*S. Magalhães, K. Lorenz, S. Pereira, M. Peres, T. Monteiro, S. Tripathy, E. Alves*
- P - 260 Investigation of structural-phase transitions dynamics on the surface of implanted silicon at rapid thermal processing**  
*Yakhya Fattakhov, Mansur Galyautdinov, Tatiana L'vova, Maksim Zakharov, Ildus Khaibullin*
- P - 264 Doubly-stacked Si Dots in SiO<sub>2</sub> Formed by Ion Beam Mixing – A Way to Improve Retention of Nanocrystal Memories**  
*Karl-Heinz Heinig, Lars Röntzsch*
- P - 274 Local structure of Fe incorporated in GaInP layers by high temperature ion implantation**  
*Tiziana Cesca, Andrea Gasparotto, Giovanni Mattei, Beatrice Fraboni, Federico Boscherini, Massimo Longo, Luciano Tarricone*
- P - 275 Ion implantation of Cs into silicon carbide: damage production and diffusion behaviour**  
*Aurégane Audren, Abdenacer Benyagoub, Lionel Thomé, Frédéric Garrido*
- P - 280 Ion irradiation effects on the electro-optical performances of interdigit vertical 4H-SiC Schottky UV photodetectors**  
*Antonella Sciuto, Fabrizio Roccaforte, Salvatore Di Franco, Vito Raineri*

- P - 281 Copper gettering by helium induced voids in silicon**  
*V.M. Vishnyakov, M.F. Beaufort, S.E. Donnelly*
- P - 286 Helium behaviour in  $\alpha$ -SiC ceramics investigated by NRA technique**  
*T. Sauvage, G. Carlot, L. Vincent, P. Garcia, G. Martin, P. Desgardin, M.F. Barthe, A. Gentils*
- P - 287 Electrical effects of high temperature Fe implantation on MOVPE GaInP/GaAs**  
*Beatrice Fraboni, Tiziana Cesca, Andrea Gasparotto, Massimo Longo, Luciano Tarricone*
- P - 288 Structural versus electrical properties of defects induced by ion implantation in germanium**  
*Stefan Decoster, F. Danie Auret, Michael Hayes, André Vantomme*
- P - 293 Ion-irradiation-induced amorphization and porosity of Germanium: GISAXS studies of structural modifications and relaxation**  
*I. Dunja Desnica-Franković, Pavo Dubcek, Maja Buljan, Uros V. Desnica, Sigrid Bernstorff, Mark C. Ridgway, Cris J. Glower*
- P - 297 Quantitative determination of electrically active concentration profile in ion-implanted GaN**  
*Ferdinando Iucolano, Filippo Giannazzo, Fabrizio Roccaforte, Lucia Romano, Maria Grazia Grimaldi, Vito Raineri*
- P - 316 Instability of junctions formed by low energy B implant and low temperature solid phase epitaxy growth**  
*Lin Shao, Yongqiang Q. Wang, Michael Nastasi, Quark Chen, K. Ma, Xiangkun K. Yu, Jiarui Liu, Wei-Kan Chu*
- P - 334 Formation process of  $\beta$ -FeSi<sub>2</sub> from amorphous Fe-Si**  
*Muneyuki Naito, Akihiko Hirata, Manabu Ishimaru, Yoshihiko Hirotsu, James A. Valdez, Kurt E. Sickafus*
- P - 339 The Yield strength of Si determined from measurements of Implantation induced strain as functions of implant temperature and ion dose**  
*Veerasamy Lakshmanasamy Raghu, Stephania Hatt, Patrick Kluth, Rakesh Dogra, Susan M. Kluth, Mark C. Ridgway*
- P - 346 Fabrication of GaAs on Si heterostructures by hydrogen implantation and direct wafer bonding**  
*H.J. Woo, H.W. Choi, G.D. Kim, W. Hong, J.K. Kim, H. R. Lee*
- P - 347 Modification of He Implantation Induced Defects using Fluorine Implantation**  
*D.I. Alquier, G. Gaudin, M.F. Beaufort, S.E. Donnelly, L. Haworth, F. Cayrel*
- P - 356 Raman spectroscopy analysis of hydrogen related defects in high dose H-implanted silicon**  
*Jeffrey C. McCallum, Daniel J. Pyke,*
- P - 360 Amorphous phase formation in ion implanted In<sub>x</sub>Ga<sub>1-x</sub>As**  
*Zohair S. Hussain, Werner Wesch, Elke Wendler, Mark C. Ridgway*
- P - 370 Defect-band-free luminescence from nano-sized ZnO fabricated by ion implantation and thermal oxidation**  
*Hiroshi Amekura, Yoshihiko Takeda, Naoki Kishimoto, Christoph Buchal*
- P - 382 Fe doping of GaN by ion implantation**  
*J. Jensen, M. Linnarsson, T. Aggerstam, S. Lourudoss, G. Possnert, A. Hallén*
- P - 388 Epitaxial re-crystallization of amorphous Si layers by swift heavy ions**  
*Pratap K. Sahoo, T. Mohanty, D. Kanjilal, V.N. Kulkarni*
- P - 390 Characterization of silicon carbide coating synthesized from Si-based polymers**  
*Masaki Sugimoto, Katsuyoshi Takano, Shunya Yamamoto, R.A. Wach, Masahito Yoshikawa*
- P - 393 Luminescence Properties of Er Implanted Silicon Nanoclusters**  
*Giorgia Franzò, Alessia Irrera, Isodiana Crupi, Francesco Priolo, Fabio Iacona, Gianfranco Di Stefano, Angelo Piana, Delfo Sanfilippo, Piergiorgio Fallica*
- P - 396 F implantation in preamorphized Si: point defect engineering and control of dopant diffusion**  
*Giuliana Impellizzeri, Salvatore Mirabella, Francesco Priolo, Enrico Napolitani, Alberto Carnera*
- P - 413 Effect of cavity-controlled vacancy supersaturations on B diffusion and activation in Si**  
*Olivier Marcelot, A. Claverie, M. Gavelle, F. Séverac, F. Cristiano, F. Cayrel, D. Alquier, W. Lerch, S. Paul, L. Rubin, H. Jaouen*
- P - 414 RBS--channeling analysis of ion--irradiation effects in laser--annealed Si:As**  
*Giorgio Lulli, Marco Bianconi, Matteo Ferri, Guglielmo Fortunato, Luigi Mariucci*
- P - 417 Growth of GaN on Ga ion implanted SiN substrates using ECR-MBE**  
*Junichi Yanagisawa, Hiroyoshi Matsumoto, Takaaki Fukuyama, Yuuki Shiraishi, Tokuo Yodo, Yoichi Akasaka*
- P - 433 Ion Implanters contamination on wafer surface analyzed by ToF-SIMS and SPV analytical techniques**  
*R. Ricciari, M. Bertini, G. Pizzo, E. Ferlito, G. Anastasi, D. Mello, G. Franco*
- P - 437 Damage recovery of GaN implanted with Mg, N and Ga ions**  
*I.O. Usov, T.G. Holesinger, D.D. Koleske, Y.Q. Wang*
- P - 438 Properties of silicon nanocrystals formed and doped by ion implantation in different oxide matrices**  
*A.I. Belov, A.V. Ershov, T.G. Finstad, O.N. Gorshkov, A.I. Kovalev, A.N. Mikhaylov, L. Pavesi, D.I. Tetelbaum, R. Turan, D.L. Wainstein*
- P - 440 Two mechanisms of nanocrystals formation under ion irradiation of silicon**  
*A.A. Ezhveskii, D.I. Tetelbaum, Yu.A. Mendeleva, D.V. Guseinov, E.V. Kiseleva*
- P - 441 Accumulation of Si at the surface during implantation of 4H SiC**  
*Anders Hallén, Yanwen Zhang*
- P - 444 Large Boron Interstitial Clusters: Dissolution Kinetics and Strain**  
*D. De Salvador, G. Bisognin, E. Napolitani, A. Carnera, E. Bruno, S. Mirabella, F. Priolo, S. Boninelli, N. Cherkashin, F. Cristiano*
- P - 447 Why the F<sup>+</sup> ion implantation can stop boron diffusion in Si?**  
*Nik Gerasimenko, Nik Gerasimenko Jr, Alex Tarasenkov, Igor Loviagin*

- P - 448 Thermo-optical effects on radiation defects in implanted silicon**  
*Nik N. Gerasimenko Jr, Nik N. Gerasimenko*
- P - 449 Fractal analysis of self-organized structures in implanted semiconductors**  
*Sergey A. Apreloy, Nik N. Gerasimenko*
- P - 454 Neon Implantation in Silicon at different Temperature**  
*S. Peripolli, L. Amaral, E. Oliviero, M.F. Beaufort, J.F. Barbot, P.F.P. Fichtner, S.E. Donnelly*
- P - 459 Damage evolution in low-energy ion-implanted silicon: comparing nanocalorimetry, reflectometry and channeling**  
*Rachid Karmouch, Yonathan Anahory, Martin Chicoine, Jean-François Mercure, François Schiettekatte*
- P - 461 Evolution of H/D-related defects in germanium implanted with high fluences of low-keV H or D ions**  
*Nicholas Desrosiers, Alexandre Giguère, Bernard Terreault*
- P - 462 Silicon swelling under low-keV hydrogen and deuterium implantation**  
*Nicholas Desrosiers, Bernard Terreault*
- P - 463 TEM investigation of nanobubbles induced by F implantation in preamorphized Si**  
*Simona Boninelli, Giuliana Impellizzeri, Salvatore Mirabella, Francesco Priolo, Enrico Napolitani, Filadelfo Cristiano*
- P - 473 Large capacitance-voltage hysteresis loops in SiO<sub>2</sub> films containing Ge nanocrystals produced by low energy ion implantation and annealing**  
*C.J. Park, K.H. Cho, W.-C. Yang, H.Y. Cho, Suk-Ho Choi, R. G. Elliman, J.H. Han, Chungwoo Kim*
- P - 481 Investigation of ion scattering from the semiconductor defect surfaces at the grazing incidence**  
*A.A. Dzhurakhalov, U.O. Kutliev, B.S. Kalandarov*
- P - 488 Deposition of Ge-C films using low-energy ion-beam induced chemical vapor deposition**  
*T. Matsutani, M. Kiuchi, T. Takeuchi*
- P - 508 Effect of strain on the carrier mobility in heavily doped p-type Si**  
*Lucia Romano, Riccardo De Bastiani, Cristina Miccoli, Gabriele Bisognin, Maria Grazia Grimaldi*
- P - 509 Boron Interstitial Clusters nucleation, growing and dissolution mechanisms**  
*Alberto Maria Piro, Lucia Romano, Salvatore Mirabella, Maria Grazia Grimaldi*
- P - 511 Nanovoids in MBE SiGe/Si epilayers induced by He ion implantation**  
*Antonio Terrasi, Gabriele Bisognin, Marina Berti, Salvatore Mirabella, D. D'Angelo, Elena Bruno, Corrado Bongiorno, Filippo Giannazzo, Vito Raineri*
- P - 513 High energy N<sup>+</sup> ion implantation in 4H-SiC**  
*Erwan Oliviero, Mihai Lazar, Alain Gardon, Christophe Peaucelle, Angela Perrat, Jean-Jacques Grob, Christophe Raynaud, Dominique Planson*
- P - 516 Amorphous-Crystalline interface evolution during Solid Phase Epitaxy Re-growth of SiGe films amorphized by ion implantation**  
*Daniele D'Angelo, Salvatore Mirabella, Corrado Bongiorno, Lucia Romano, Alberto Piro, Antonio Terrasi, Maria Grazia Grimaldi*
- P - 518 Si-Self interstitial diffusion in crystalline silicon at room temperature**  
*Alberto Maria Piro, Lucia Romano, Salvatore Mirabella, Maria Grazia Grimaldi*
- P - 523 Photoluminescence of He-implanted ZnO nanocrystals**  
*J.-K. Lee, D.A. Lucca, T.A. Harriman, M. Nastasi*
- P - 534 Ultra deep trench doping in silicon by grazing incident boron implantation**  
*S. Nizou, M. Ziti, J.M. Lecoq, M. Roy, D. Alquier*
- P - 536 Trap efficiency in ion irradiated 4H-SiC**  
*L. Calcagno, A. Ruggiero, P. Musumeci, G. Cuttone, G. Foti*
- P - 549 Effect of energetic ions on the stability of bond-center hydrogen in silicon**  
*S.V.S. Nageswara Rao, S.K. Dixit, G. Lüpke, L.C. Feldman, N.H. Tolk*
- P - 550 Effects of dopants on the amorphous-to-fcc transition in Ge<sub>2</sub>Sb<sub>2</sub>Te<sub>5</sub> thin films**  
*S. Privitera, E. Rimini, C. Bongiorno, A. Pirovano, R. Bez*